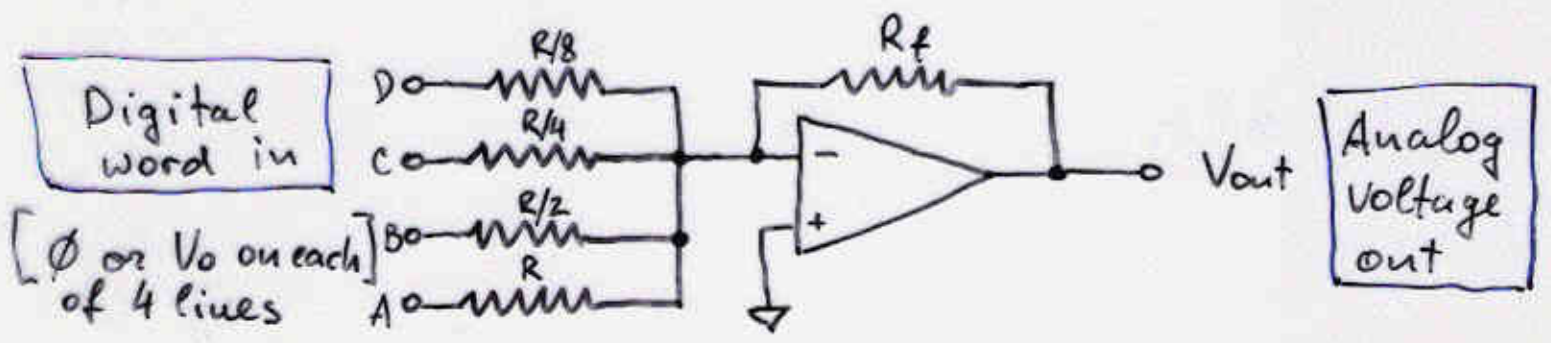


# A/D and D/A conversion

## D/A converter



weighted-resistor ladder network

$$V_{out} = -V_o \frac{R_f}{R} [A \cdot 1 + B \cdot 2 + C \cdot 4 + D \cdot 8]$$

BCD coding!

$(DCBA)_{10}$	DCBA	$V_{out}$
$\emptyset$	0000	-0.0V
1	0001	-0.5V
2	0010	-1.0V
3	0011	-1.5V
.....		
8	1000	-4.0V
9	1001	-4.5V

@  $R_f = R/8$   
 $V_o = +4.0V$

### Notes:

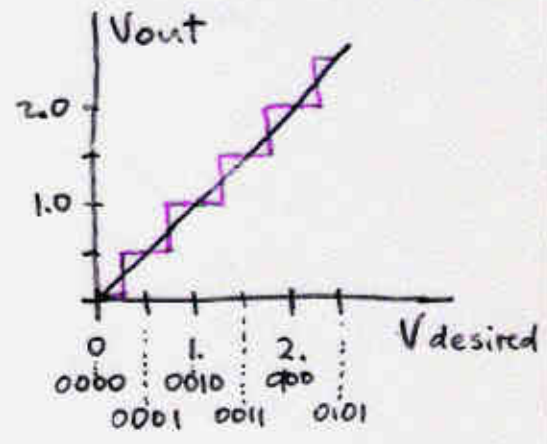
- adjust  $R_f$  to avoid saturation
- need good precision resistors
- resolution of an n-bit converter  $\approx \frac{1}{2^n}$

E.g. here  $\frac{1}{2^4} = \frac{1}{16} = 6.25\%$  i.e.  $\pm 3.125\%$  is the inherent uncertainty of the digital representation  
 →  $R_f$  should be at least as good, so that the scale of output reflects the accuracy of input

- ladder resistors should be good enough to distinguish adjacent voltage values. E.g., for bit D: value = "8", i.e.  $7\frac{1}{2} < R_D < 8\frac{1}{2}$

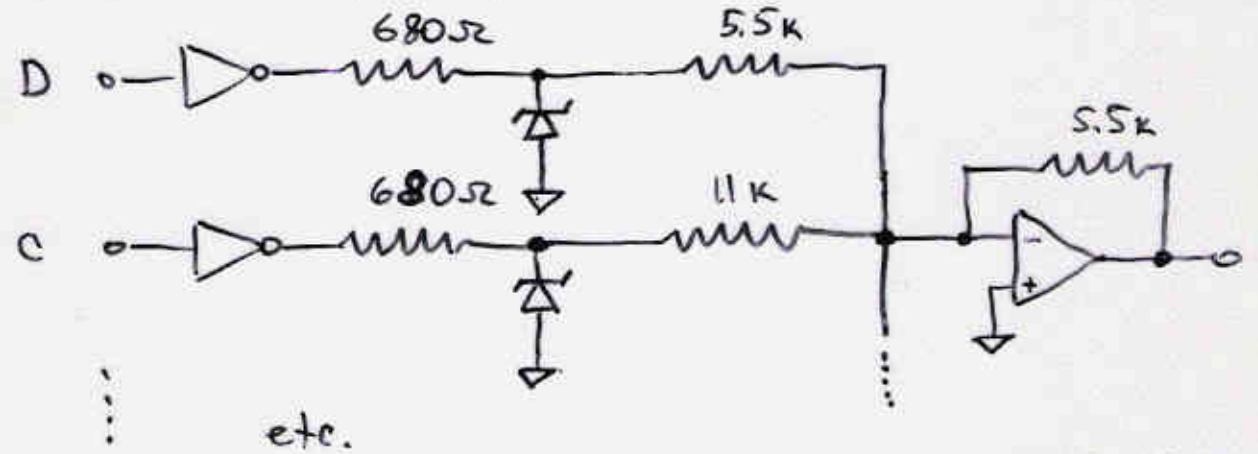
**EFTS**: is the tolerance for  $R_A$  higher or lower?

- the output of DAC varies in steps, not continuously:  
To reduce the size of steps need to use a higher # of bits.



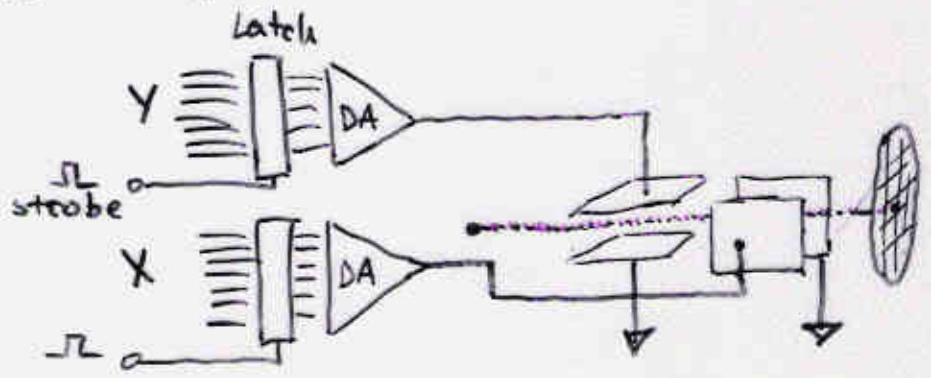
- need good reference  $V_0$  to have reproducible  $V_{out}$ , not usually available in digital circuits!

⇒ use diodes for precise level control:

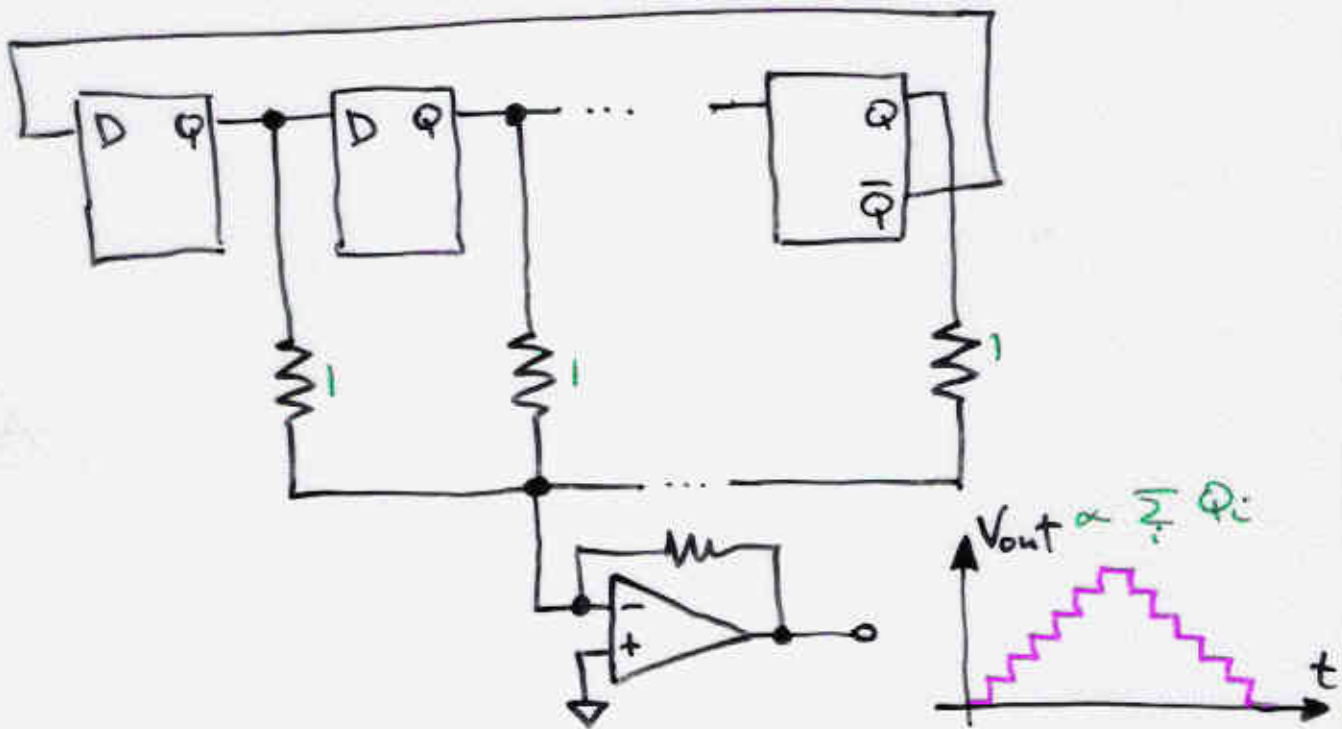


In this typical design, the voltage level of each logic bit is = 0.7V rather than  $3.5 \div 5.0V$ .

- use to control XY-displays (plotter, CRT)

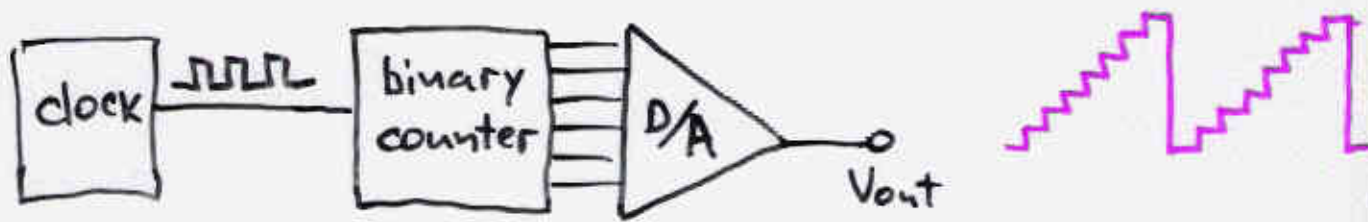


Ex Johnson counter, revisited

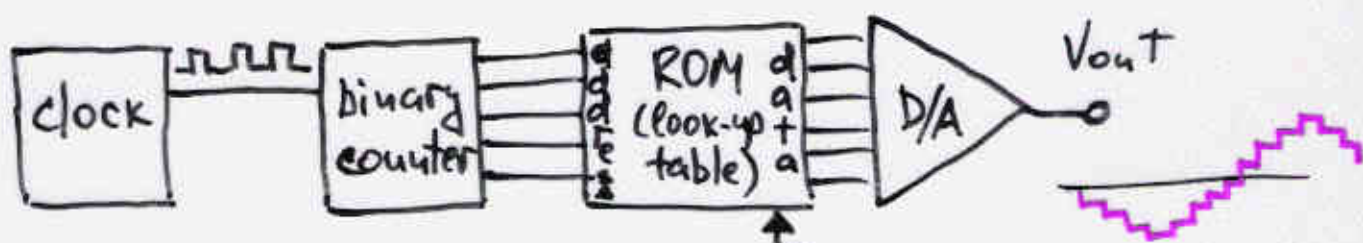


⇒ a triangular analog wave generator

Ex saw-tooth waveform generator

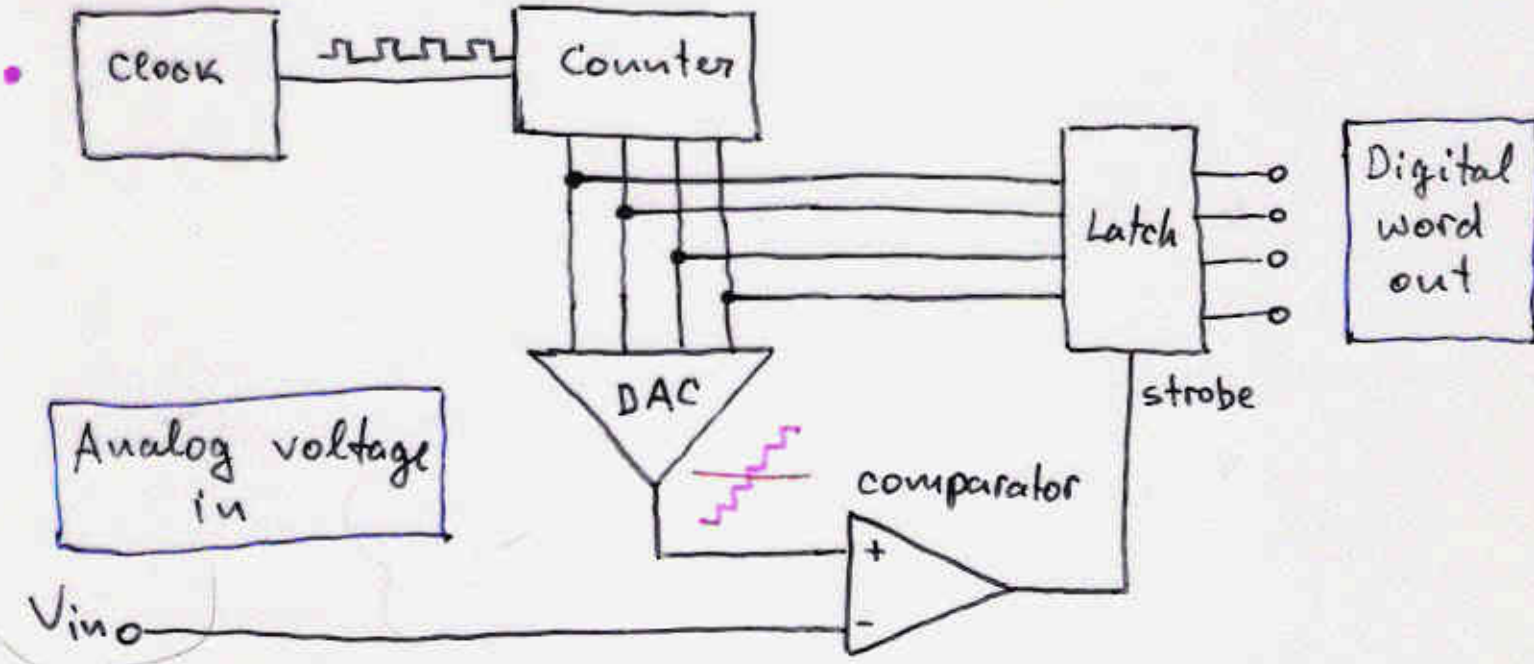


Ex arbitrary waveform generator

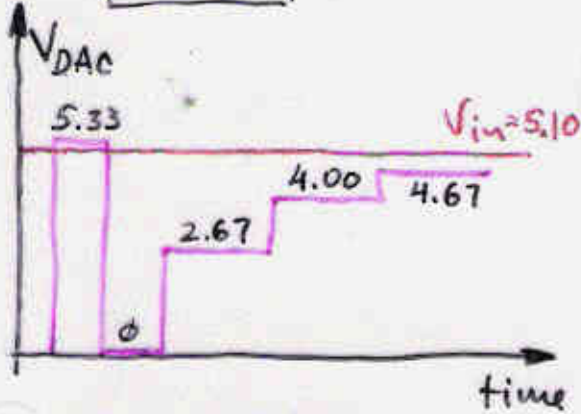
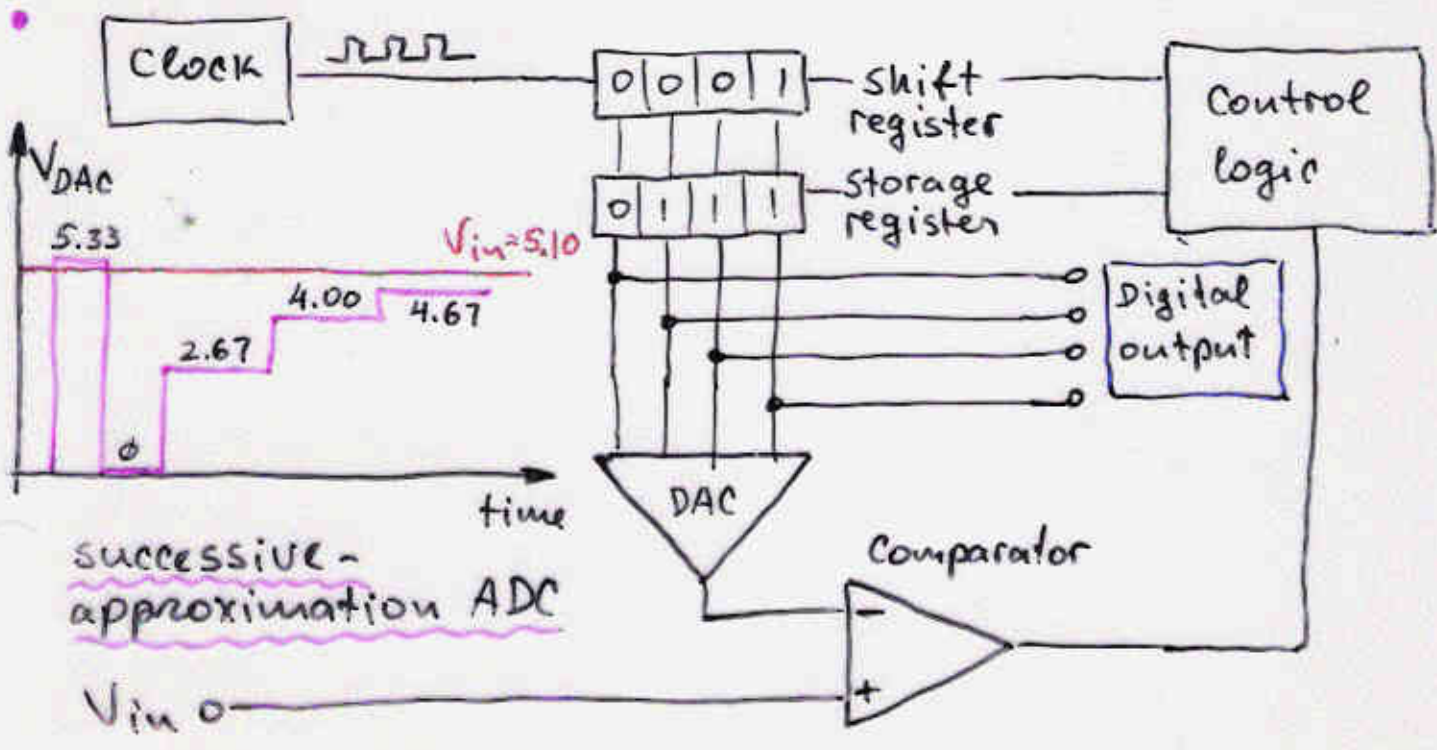


e.g. a sine wave look-up

# A/D converters



- this is "tracking ADC": count until  $V_{in} = V_{DAC}$
- slow for high-resolution DACs (large # of small steps)
- can improve by counting up and down, depending on the output of the comparator.

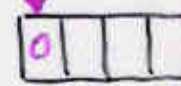


successive-approximation ADC

## 4-bit successive approximation A/D on $\phi$ -10V range.

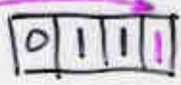
0000	0001	0010	0100	1000	1111
$\phi$ V	0.67V	1.33V	2.67V	5.33V	10V

- perform a series of comparisons between the analog  $V_{in} = 5.10V$  and a series of reference voltages. If reference =  $V_{DAC} \leq V_{in}$ , an appropriate bit is set to "1".

1. try 1000 = 5.33V. Too large  $\Rightarrow$  MSB = "0" 

2. try 0100 = 2.67V. Too small  $\Rightarrow$  2<sup>nd</sup> MSB = "1" 

3. try 0110 = 4.00V. Too small  $\Rightarrow$  3<sup>rd</sup> MSB = "1" 

4. try 0111 = 4.67V. Too small  $\Rightarrow$  4<sup>th</sup> MSB = "1" 

5. report "0111" (= 4.67V) as the digital representation of  $V_{in} = 5.10V$ , i.e. "5.10V  $\approx$  4.67V"

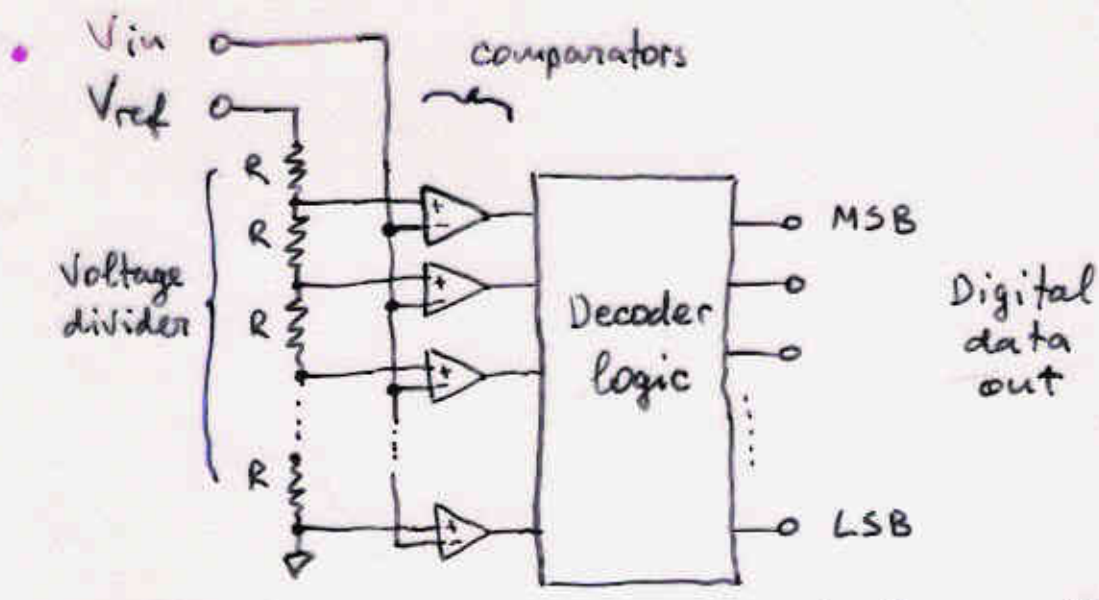
- precision: 1 part in  $2^4$  or 625mV in 10V  
i.e. the smallest step = 625mV.

$\Rightarrow$  5.10 = "somewhere between 4.67 and 5.33"

- resolution:  $\frac{1}{2}$  smallest step = 312mV, i.e. two analog values 312mV apart will be distinguished, but their absolute values known to within 625mV

- ADC levels are "quantized"  $\Rightarrow$  quantization noise, or "waffling" of the digital output between two adjacent levels which bracket the true value

- max error when input is  $\frac{1}{2}$  way between levels



**EFTS**  
 Design the Decoder logic for a 2-bit flash ADC

- this is the "flash converter": all bits are processed in parallel. Conversion time only limited by the propagation delays in the logic, but circuitry more complex

• comparison

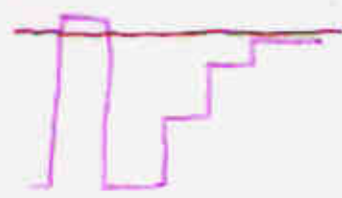
tracking

- cheap, simple
- slow-varying signals only
- worst-case:  $2^n - 1$  steps



succ. approx.

- moderate \$
- \$30-100 for 8-12 bit
- wide range of sampling rates
- conversion in  $n$  steps



flash

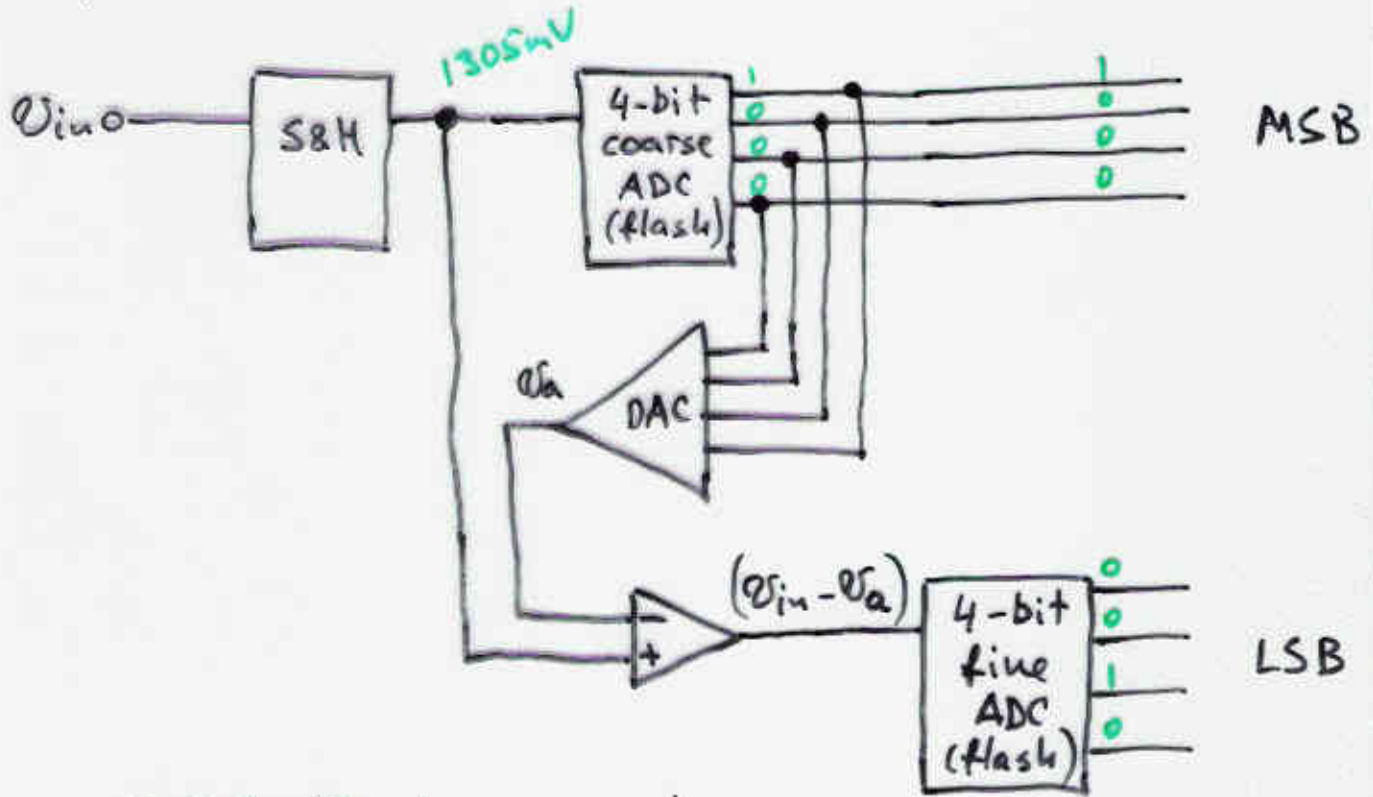
- complex, \$\$
- capable of very fast conversions, in 1 step.



• only unipolar, BCD used above. Other coding schemes and bipolar possible. E.g. 2's complement, and  $\overline{00000000}$  for a flash ADC

$+V_{ref}$        $-V_{ref}$

• parallel-series ADC



One 8-bit flash converter

- 255 comparators in a ladder

Two 4-bit flash converters

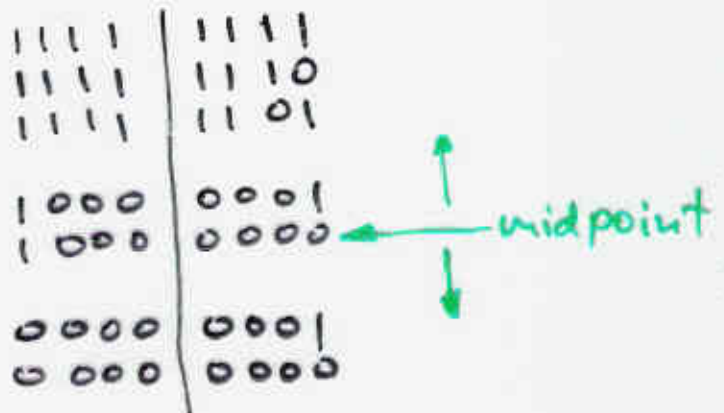
- $2 \times 15 = 30$  comparators

The down side :

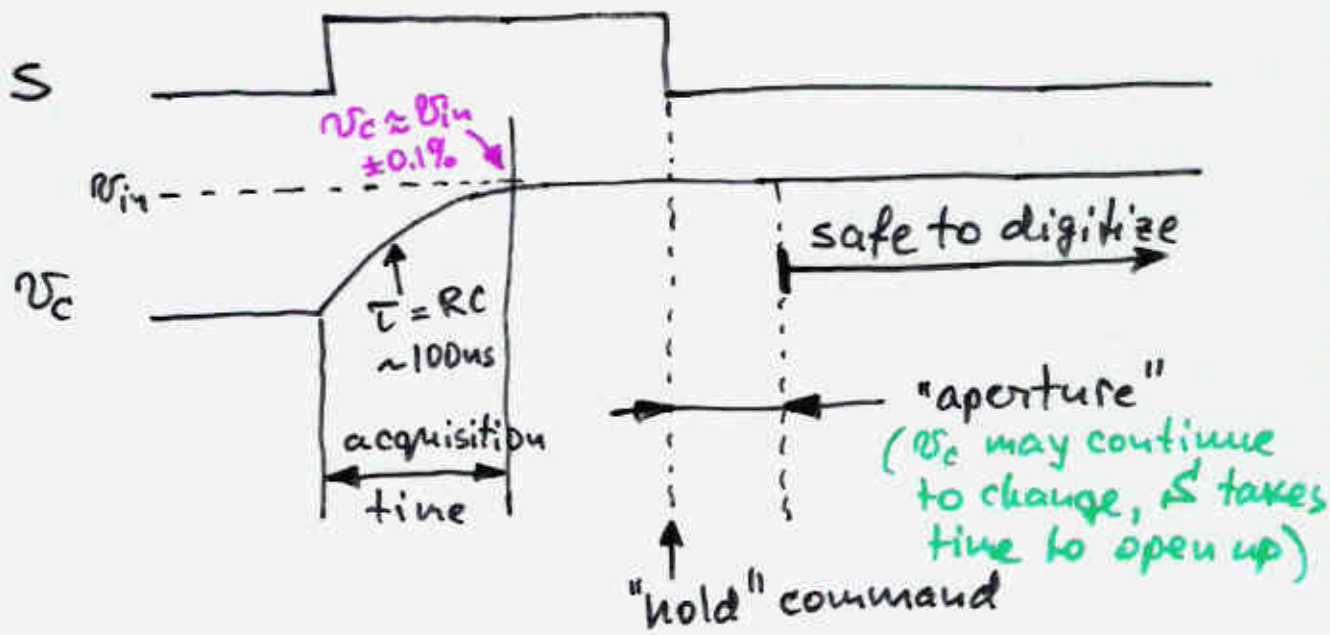
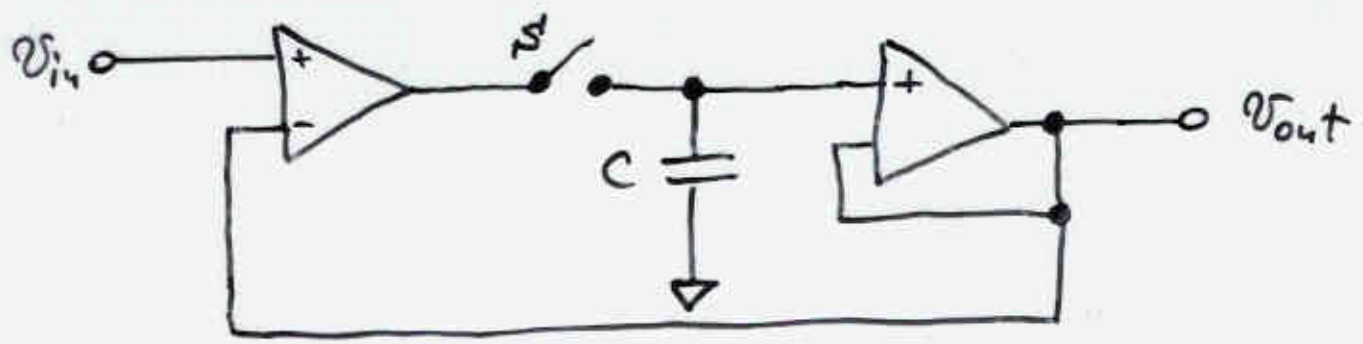
- extra components : DAC, fast analog subtractor, S&H

Ex  $LSB = 10mV$ ,  $V_{in} = 1305mV$


- $2550 \leq V_{in}$
- $2540 \leq V_{in} < 2550$
- $2530 \leq V_{in} < 2540$
- .....
- $1290 \leq V_{in} < 1300$
- $1280 \leq V_{in} < 1270$
- .....
- $10 \leq V_{in} < 20$
- $0 \leq V_{in} < 10$



• sample-and-hold amplifier



• A/D parameters

- quantization (digital) error :  $\pm \frac{1}{2}$  LSB typ.
- accuracy :  $\pm 1$  LSB typ, or % of full scale
- linearity   $\pm \frac{1}{2}$  LSB is the best possible,  $\pm 1$  LSB typ

[ a common cause of non-linearity is a missing output code, spikes - i.e. non-monotonicity as well as non-linearity ]



- Resolution :  $2^N$  levels,  $2^N - 1$  steps

$$\frac{1}{2^N - 1} \approx \frac{1}{2^N}$$

No. bits	No. steps = $2^N - 1$	LSB, % full scale	Dyn. range, dB
8	255	0.39	48
10	1023	0.098	60
12	4095	0.024	72
14	16383	0.0061	84
16	65535	0.0015	96

ref  
Simpson  
p. 744

- Dynamic range :  $\frac{V_{largest}}{V_{smallest}}$ , usually in dB

$$D.R. = 20 \log \frac{2^N - 1}{1} \approx 20 \log 2^N$$

- conversion time
- throughput
- S/H droop

Ex I/O board for interfacing a computer to an experiment

